



Power MOSFETS

DATASHEET

LM1CD40NAI8A

N-Channel
Enhancement Mode MOSFET

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Quality Management Systems
ISO 9001:2015 Certificate

LM1CD40NAI8A

N-Channel Enhancement Mode MOSFET

Pin Description

Product Summary

Symbol	Symbol	N-Channel	Unit
		V _{DSS}	V
		R _{DS(ON)-Max}	mΩ
		I _D	A

Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

Applications

- Power Management in DC/DC Converters
- Motor control
- Disconnect switches

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1CD40NAI8A	PDFN3.3*3.3	Tape & Reel	5000 / Tape & Reel	1CD40 <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/>

Note : = Lot Code

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter		N-Channel	Unit
V _{DSS}	Drain-Source Voltage		120	V
V _{GSS}	Gate-Source Voltage		±20	
T _J	Maximum Junction Temperature		150	°C
T _{STG}	Storage Temperature Range		-55 to 150	°C
I _S	Diode Continuous Forward Current	T _c =25°C	11.4	A
I _{DM} ⁽¹⁾	Pulse Drain Current Tested	T _c =25°C	13.3	A
I _D	Continuous Drain Current	T _c =25°C	5.3	A
		T _c =100°C	3.4	
P _D	Maximum Power Dissipation	T _c =25°C	12.5	W
		T _c =100°C	5.0	
I _D	Continuous Drain Current	T _A =25°C	1.9	A
		T _A =70°C	1.5	
P _D	Maximum Power Dissipation	T _A =25°C	1.6	W
		T _A =70°C	1.0	
I _{AS} ⁽²⁾	Avalanche Current, Single pulse	L=0.1mH	2.5	A
		L=0.5mH	2	
E _{AS} ⁽²⁾	Avalanche Energy, Single pulse	L=0.1mH	0.3	mJ
		L=0.5mH	1	

Thermal Characteristics

Symbol	Parameter		Rating	Unit
R _{θJC}	Thermal Resistance-Junction to Case	Steady State	10	°C/W
R _{θJA} ⁽³⁾	Thermal Resistance-Junction to Ambient	Steady State	80	°C/W

Note ① : Max. current is limited by junction temperature

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz

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N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{DS}}=250\mu\text{A}$	120	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=96\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{DS}}=250\mu\text{A}$	1	2	3	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$R_{\text{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}$, $I_{\text{DS}}=1\text{A}$	-	390	440	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_{\text{DS}}=0.5\text{A}$	-	400	495	
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_{\text{DS}}=0.2\text{A}$		1	-	S
Dynamic Characteristics [®]						
R_{G}	Gate Resistance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=0\text{V}$, Freq.=1MHz	-	4	-	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=60\text{V}$, Freq.=1MHz	-	233	-	pF
C_{oss}	Output Capacitance		-	14	-	
C_{rss}	Reverse Transfer Capacitance		-	9	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{GS}}=10\text{V}$, $V_{\text{DS}}=25\text{V}$, $I_{\text{D}}=1\text{A}$, $R_{\text{GEN}}=1\Omega$	-	4.3	-	nS
t_{r}	Turn-on Rise Time		-	2.6	-	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	10.9	-	
t_{f}	Turn-off Fall Time		-	11.7	-	
Q_{g}	Total Gate Charge	$V_{\text{GS}}=4.5\text{V}$, $V_{\text{DS}}=60\text{V}$ $I_{\text{D}}=1\text{A}$	-	2.5	-	nC
Q_{g}	Total Gate Charge	$V_{\text{GS}}=10\text{V}$, $V_{\text{DS}}=60\text{V}$, $I_{\text{D}}=1\text{A}$	-	5.4	-	
Q_{gs}	Gate-Source Charge		-	1.1	-	
Q_{gd}	Gate-Drain Charge		-	0.7	-	
Source-Drain Characteristics						
$V_{\text{SD}}^{\circledast}$	Diode Forward Voltage	$I_{\text{SD}}=0.5\text{A}$, $V_{\text{GS}}=0\text{V}$	-	0.75	1.1	V
t_{rr}	Reverse Recovery Time	$I_{\text{F}}=1\text{A}$, $V_{\text{R}}=60\text{V}$	-	20.1	-	nS
Q_{rr}	Reverse Recovery Charge	$dI_{\text{F}}/dt=100\text{A}/\mu\text{s}$	-	14.6	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

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N-Channel Typical Characteristics

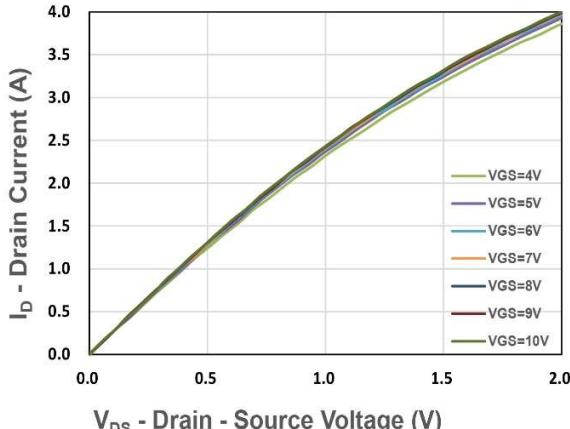


Figure 1. Output Characteristics

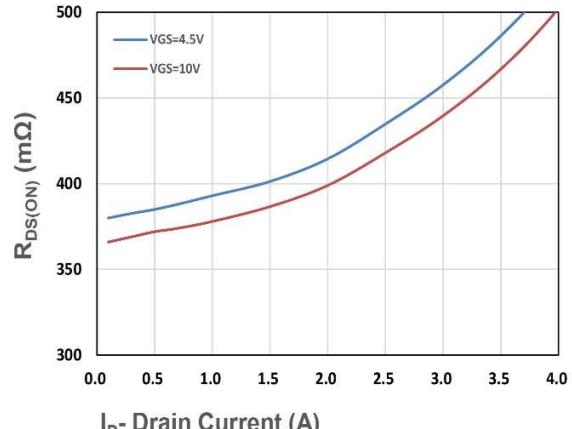


Figure 2. On-Resistance vs. ID

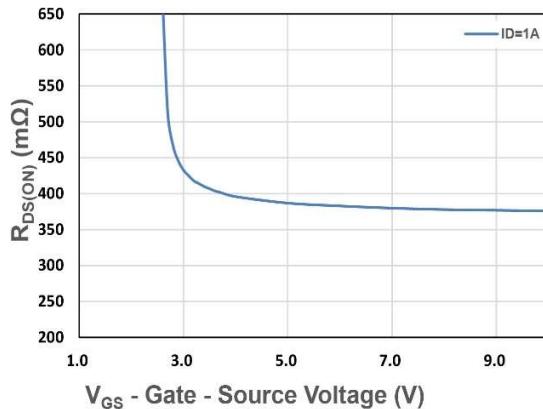


Figure 3. On-Resistance vs. VGS

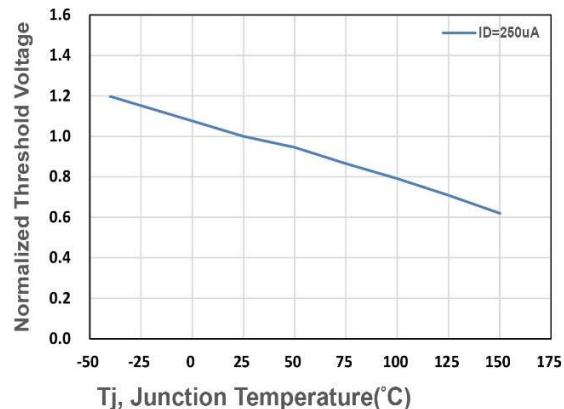


Figure 4. Gate Threshold Voltage

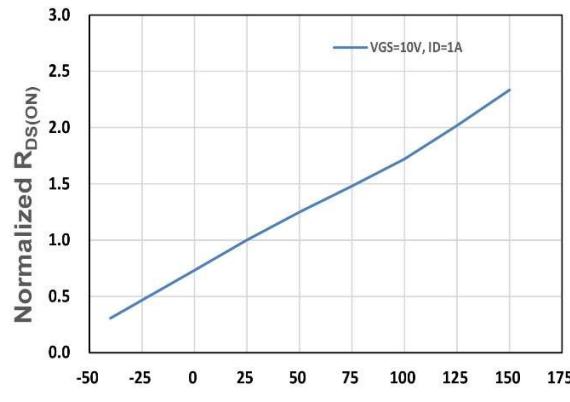


Figure 5. Drain-Source On Resistance

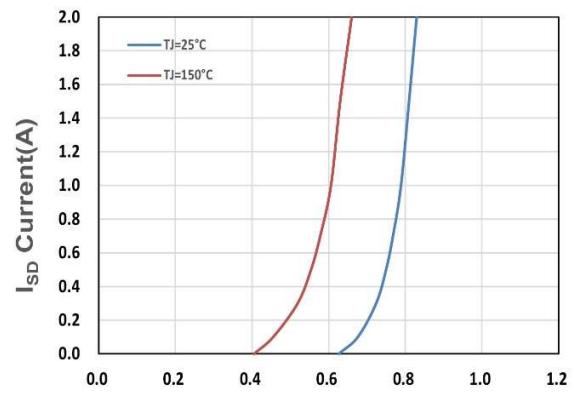
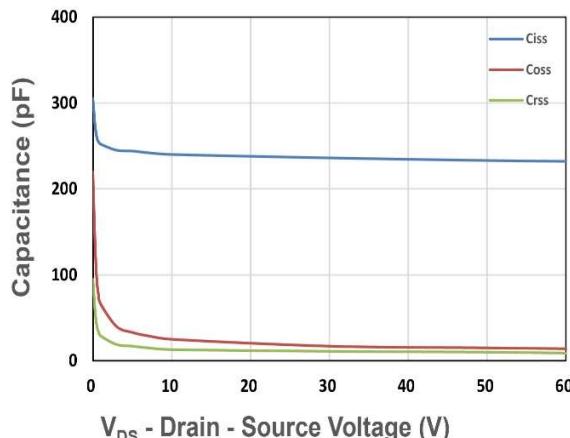


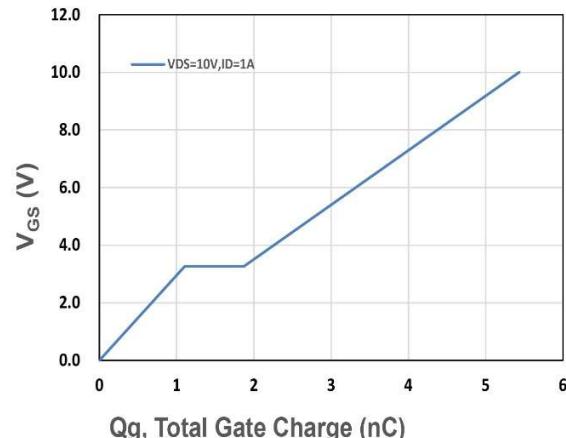
Figure 6. Source-Drain Diode Forward

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V_{DS} - Drain - Source Voltage (V)

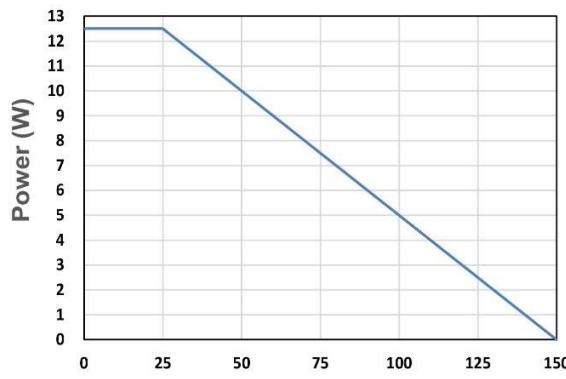
Figure 7. Capacitance



V_{GS} (V)

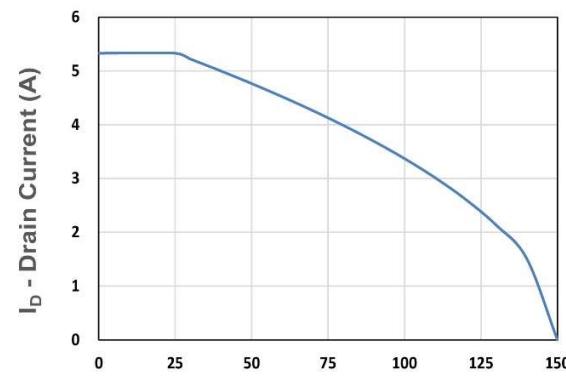
Q_g, Total Gate Charge (nC)

Figure 8. Gate Charge Characteristics



T_c - Case Temperature (°C)

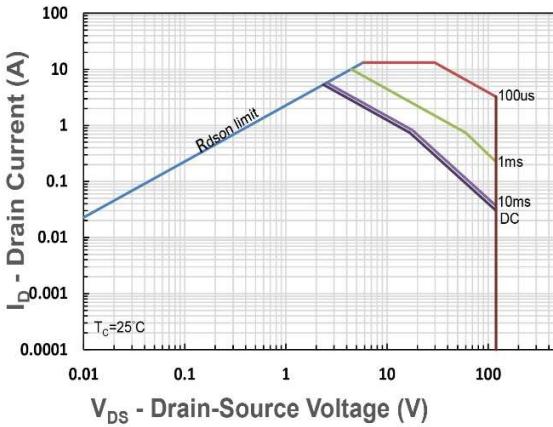
Figure 9. Power Dissipation



I_D - Drain Current (A)

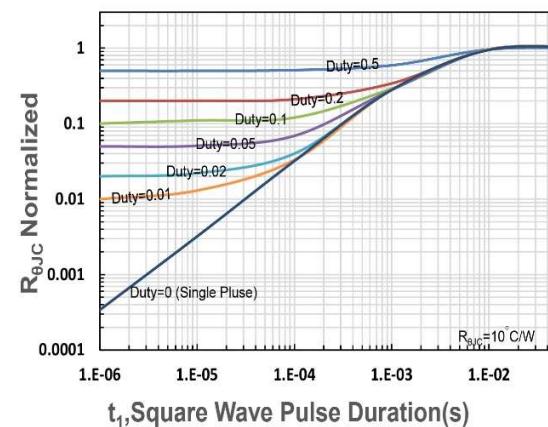
T_c - Case Temperature (°C)

Figure 10. Drain Current



V_{DS} - Drain-Source Voltage (V)

Figure 11. Safe Operating Area



t₁, Square Wave Pulse Duration(s)

Figure 12. R_{eJC} Transient Thermal Impedance